

Notice of References Cited	Application/Control No.		Applicant(s)/Patent Under Reexamination TAMURA ET AL.	
	10/804,756			
	Examiner Jacques Veillard		Art Unit 2165	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,950,915	09-2005	Ohno et al.	711/162
*	B	US-7,114,046	09-2006	Ido et al.	711/162
*	C	US-5,544,347	08-1996	Yanai et al.	711/162
*	D	US-5,729,761	03-1998	Murata et al.	710/14
*	E	US-5,890,204	03-1999	Ofer et al.	711/111
*	F	US-6,009,466	12-1999	Axberg et al.	709/220
*	G	US-6,353,878	03-2002	Dunham, Scott R.	711/162
*	H	US-6,393,483	05-2002	Latif et al.	709/226
*	I	US-6,393,519	05-2002	Fujimoto et al.	711/113
*	J	US-6,421,711	07-2002	Blumenau et al.	709/213
*	K	US-7,107,298	09-2006	Prahlad et al.	707/204
*	L	US-7,096,269	08-2006	Yamagami, Kenji	709/229
*	M	US-6,728,848	04-2004	Tamura et al.	711/162

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.